	Type	Hits	Search Text
1	IS&R	0	(257/*).CCLS.
2	IS&R	854	(257/48).CCLS.
3	IS&R	793	(257/48).CCLS.
4	IS&R	6438	(257/401,408,900,336,900,296,341,342,344,390-392).CCLS.
5	BRS	0	257/401,408,900,336,900,296,341,342,344,390-392.CCLS. and (oxide adj test)
6	BRS	265	257/401,408,900,336,900,296,341,342,344,390-392.CCLS. and (gate) and (test)
7	BRS	241	257/401,408,900,336,900,296,341,342,344,390-392.CCLS. and (gate) and (test)
8	BRS	299	257/401,408,900,336,900,296,341,342,344,390-392.CCLS. and (gate) and (test or testing)
9	IS&R	240	(365/185.1,285.33).CCLS.
10	IS&R	239	(365/185.1,285.33).CCLS.
11	IS&R	1072	(365/185.1,185.33).CCLS.
12	BRS	62422	(test) and (gate)
13	BRS	188892	(test or testing).ti.
14	BRS	7921	((test or testing) with (integrated)).ti.
15	BRS	16	((test or testing) with (integrated adj electronic)).ti.
16	BRS	16	((test or testing) with (integrated adj electronic)).ti.
17	BRS	6232	((test or testing) with (device) with (semi$1conductor)).ti.
18	BRS	840	((test or testing) adj ((device) near (semi$1conductor))).ti.
19	BRS	0	((test adj device) adj ((device) near (semi$1conductor))).ti.

	DBs	Time Stamp	Comments	Error Definition
1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/20 11:01		
2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 14:43		
3	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:25		
4	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:27		
5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:29		
6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:30		
7	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:30		
8	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:56		
9	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:56		
10	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 15:57		
11	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:41		
12	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:42		
13	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:42		
14	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:43		
15	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:43		
16	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:44		
17	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:44		
18	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:46		
19	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:47		

	Errors
1	0
2	0
3	0
4	0
5	0
6	0
7	0
8	0
9	0
10	0
11	0
12	0
13	0
14	0
15	0
16	0
17	0
18	0
19	0

	Type	Hits	Search Text
20	BRS	232	((test adj device) with ((device) near (semi$1conductor))).ti.
21	IS&R	434	(365/185.09).CCLS.
22	IS&R	413	(365/185.09).CCLS.
23	IS&R	451	(257/797).CCLS.
24	IS&R	534	(324/557-559).CCLS.
25	BRS	380	oxide adj2 gates
26	BRS	362	oxide adj2 gates
27	BRS	10	"5681770"
28	IS&R	2	("5681770").PN.

	DBs	Time Stamp	Comments	Error Definition
20	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:50		
21	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 16:50		
22	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 17:04		
23	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 17:22		
24	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/19 17:23		
25	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/20 11:02		
26	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/20 12:07		
27	USPAT; EPO; JPO; DERWENT; IBM_TDB	2002/09/20 12:08		
28	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/09/20 12:08		

	Errors
20	0
21	0
22	0
23	0
24	0
25	0
26	0
27	0
28	0